# Sample Results Summary Sheet

## Please return this form to the Curator for each allocated Sample

**Sample ID:** RA-QD02-0120

**PI:** Masayuki Uesugi

**Type and date of analysis performed:**

FIB sectioning (2013, Jul. 13, 14, Sep. 14, Oct. 14, Nov. 13)

**Elements or phases identified:** (Mg, Si, olivine, pyroxene, aromatic carbon, etc.)

N/A

**Contaminant phases identified**: (Al, SUS, carbon particles, etc.)

N/A

**Sample handling:** (e.g. exposed in atmosphere, embedded in resin, polished, sliced by FIB or UMT)

Pressed on Au plate (3mm diameter and 0.3mm thick) by Sapphire glass

Sectioned by Focused Ion Beam (FIB) (4 ultra-thin sections were extracted).

**State of sample pre-analysis:**

N2 hold. On Au coated sapphire glass.

**State of sample post-analysis:**

RA-QD02-0120:pressed on Au plate, partially sectioned by FIB, damaged by Ga beam, N2 hold in sample holder

RA-QD02-0120-01: UTS by FIB, lost during FIB sectioning

RA-QD02-0120-02: UTS by FIB

RA-QD02-0120-03: UTS by FIB

RA-QD02-0120-04: UTS by FIB

**Analysis data Notes:** (summary of the attached analysis data and/or images)

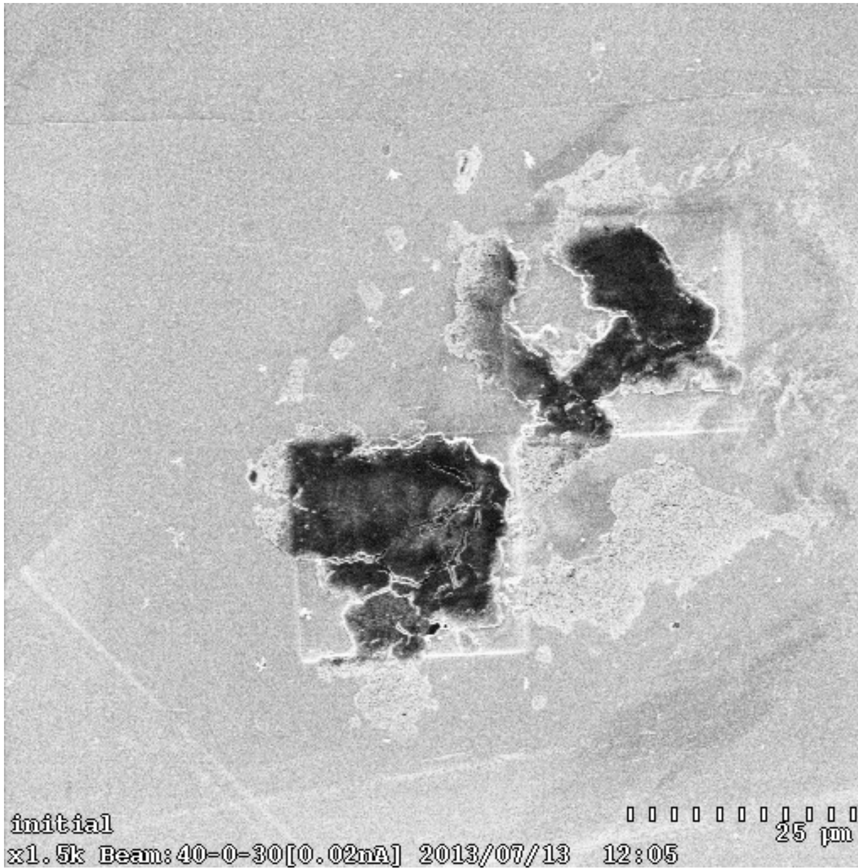


Fig.1 A scanning Ion microscope (SIM) image of RA-QD02-0120 after pressing on Au plate

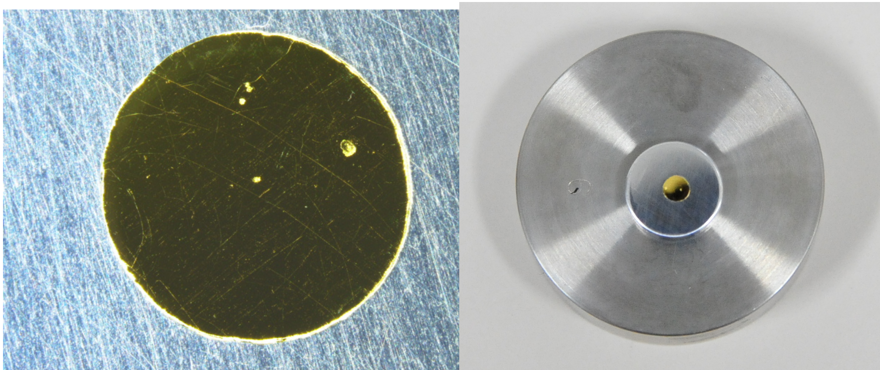

Fig. 2 Whole view of Au plate and the sample holder. Standards for NanoSIMS analysis were also pressed on the Au plate (upper and right of the Au plate). The Au plate was pressed and fixed on a half-inch stab holder.

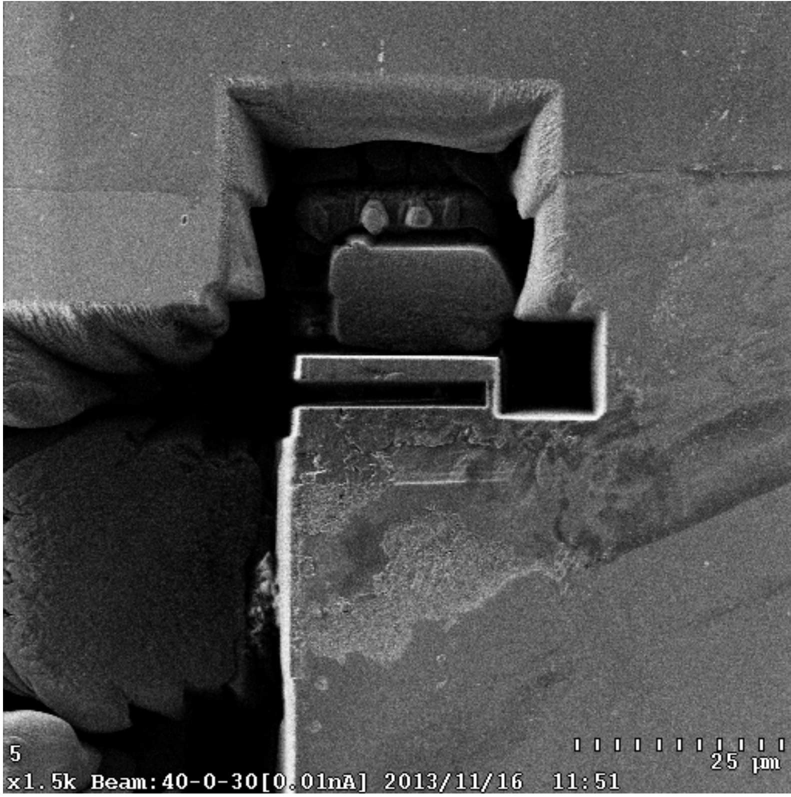


Fig. 3 SIM image of extraction of RA-QD02-0120-04 by FIB fabrication (final condition of RA-QD02-0120).